

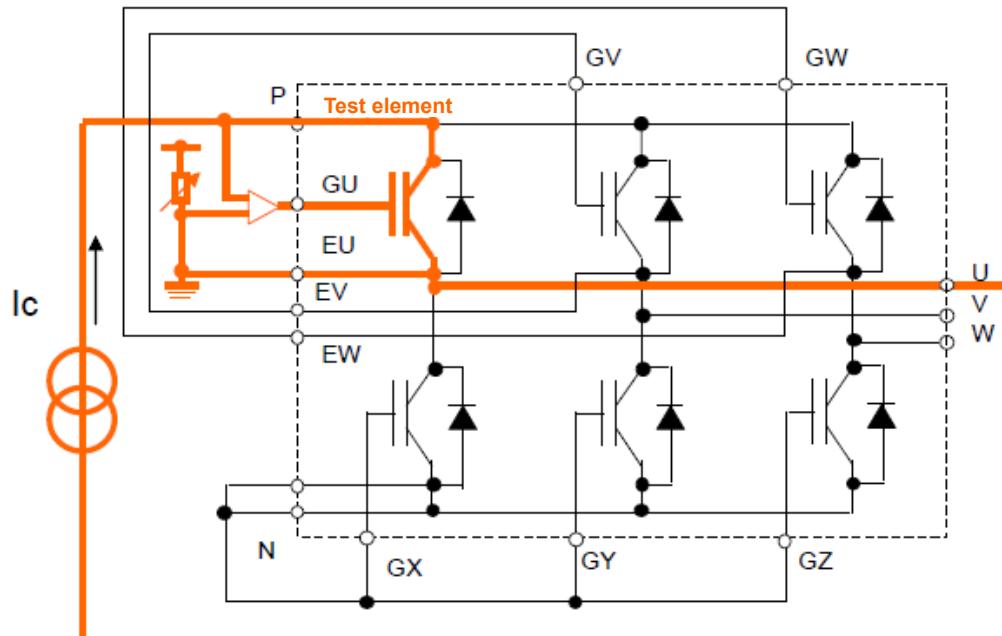
FUJI IGBT Modules U Series

Technical Documents

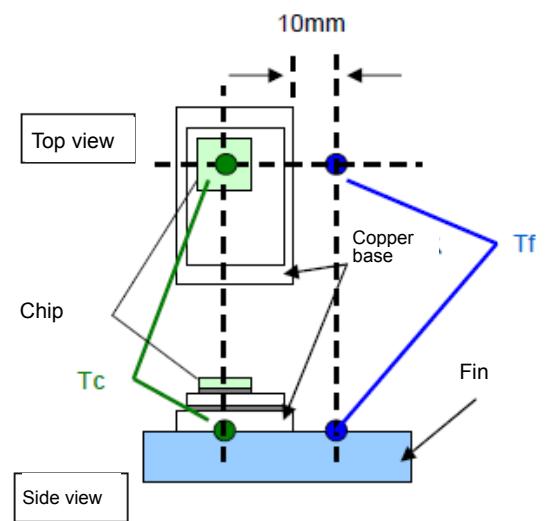
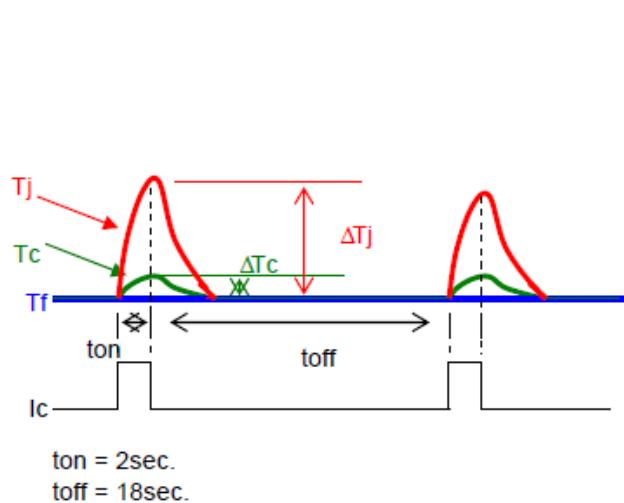
Power cycle capability	MT5Z02525c
RBSOA, SCSOA	MT5F13198
High current output-characteristics	MT5F13582
Short circuit current vs V_{GE} characteristics	MT5F14993
2 in one-package module parallel connection application	MT5F14514
Switching loss, dv/dt vs C_{GE} , R_G	MT5F14571
$-V_{GE}$ vs switching loss characteristics	MT5F13288
Dependence of blocking and junction temp.	MT5F13015
V_{CES} vs T_j characteristics	MT5F14432
$-dI_c/dt$ vs T_j characteristics	MT5F14433
Dynamic avalanche voltage vs T_j characteristics	MT5F14434
Transient thermal impedance	MT5F14621

- Fuji IGBT Module U and V Series -

ΔT_j power cycle test method and lifetime curve (technical reference material)

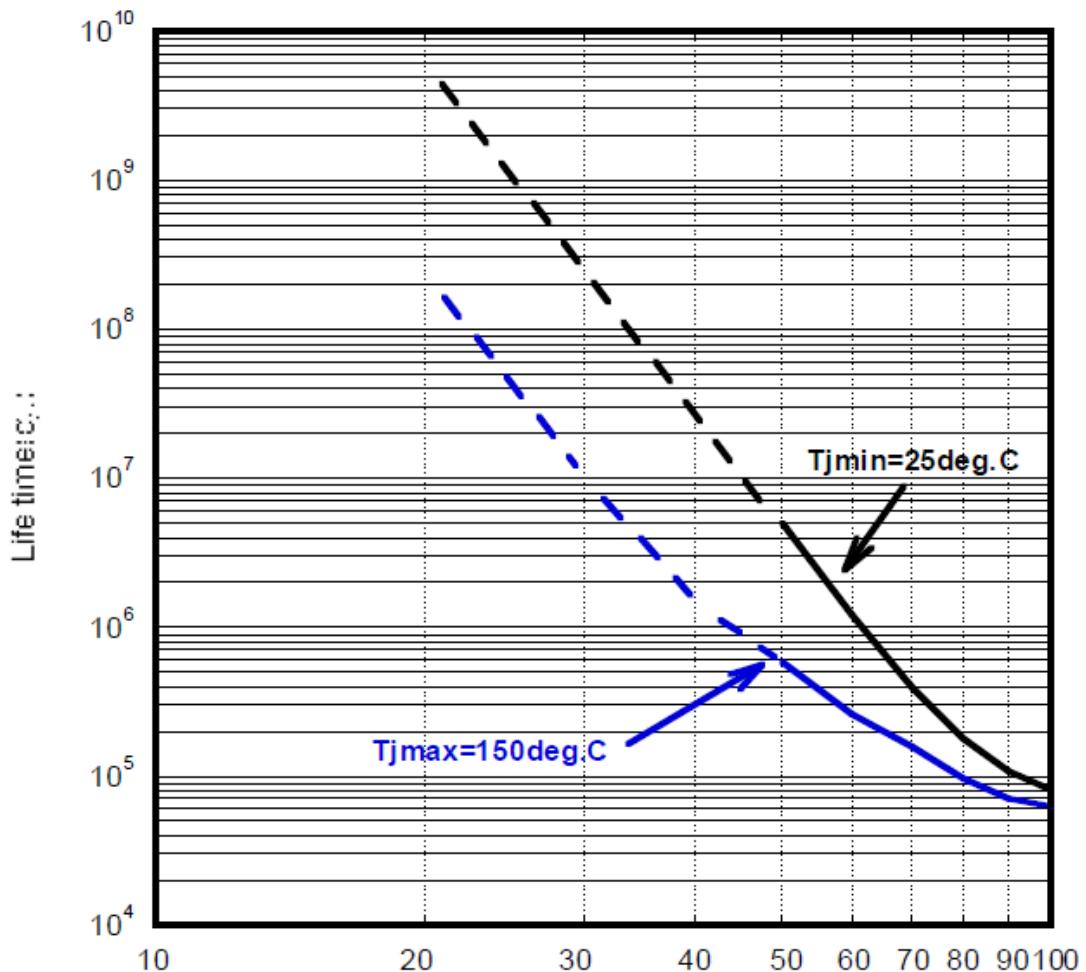


Test equivalent circuit



Current flow pattern of ΔT_j power cycle and temperature change

T_c and T_f measurement positions

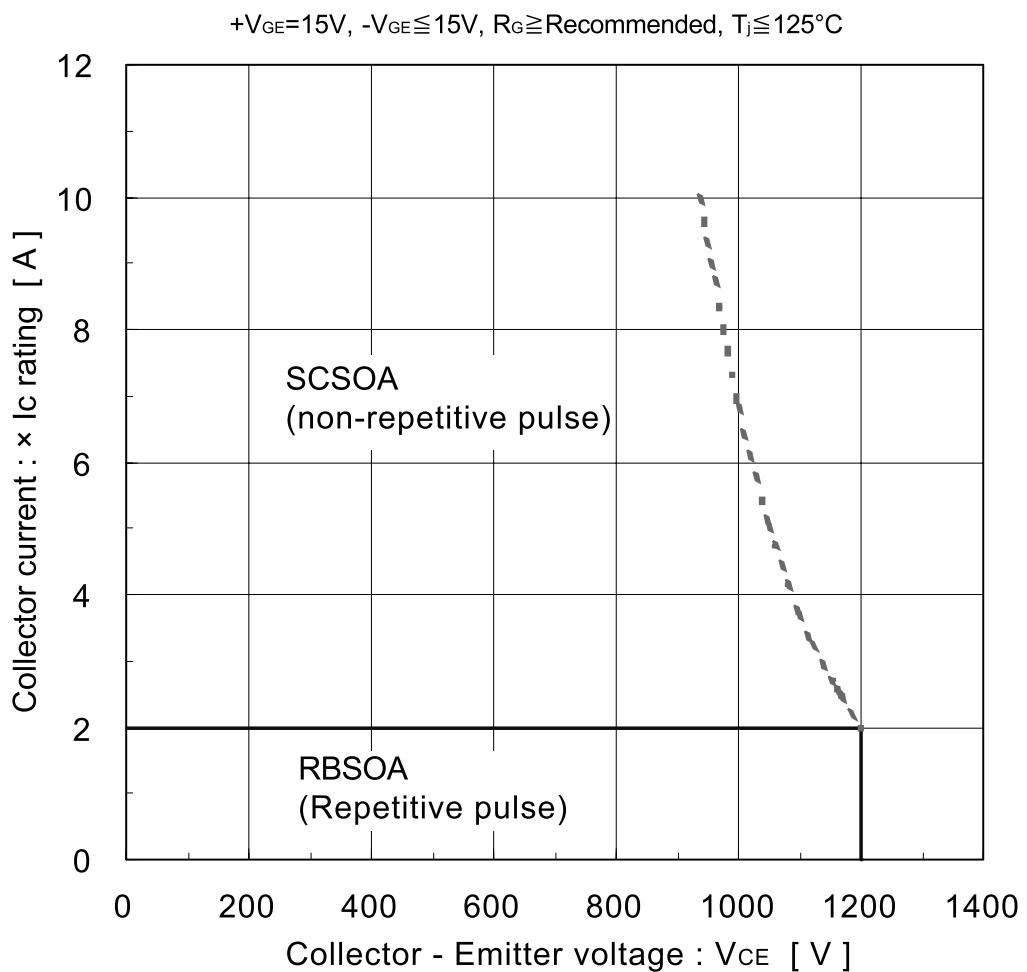


ΔT_j (deg.C)

ΔT_j Power cycling life time curve

- *1) The judgment criterion for failure is the point when the test element becomes open or short.
- *2) The radiation fin and module are mounted according to our test standards.
- *3) The capacity data in the lifetime curve is the one when the failure rate is 1% in the Weibull analysis.
- *4) The capacity data in the lifetime curve shows the result of multiple models.
- *5) The dotted lines show the estimated lifetime, not the guaranteed value.
- *6) The IGBT (FWD) chips connected in parallel are not included.

FUJI IGBT Modules U Series
RBSOA, SCSOA 1200V



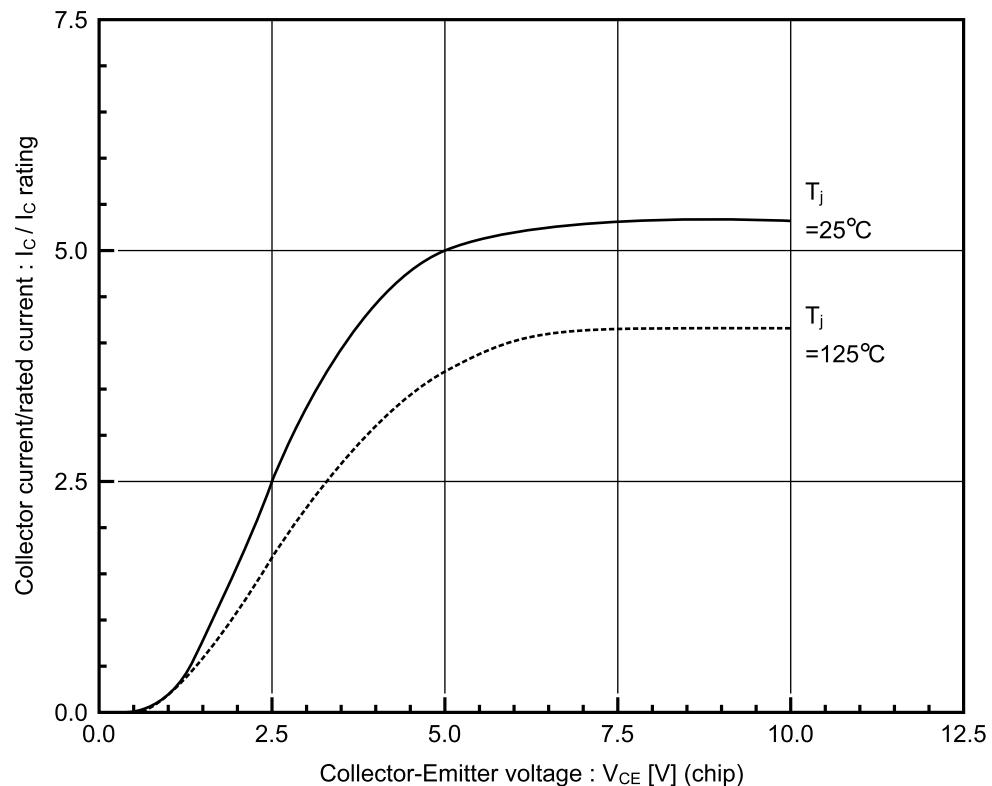
FUJI IGBT Modules U Series

High current output-characteristics 1200V Typical value

Conditions: $T_j=25/125^\circ\text{C}$

$V_{GE}=15\text{V}$

Not include internal-drop voltage due to internal-resistance of module.



FUJI IGBT Modules U Series

Short circuit vs V_{GE} characteristics 1200V

Sample: 2MBI150UA-120, 2MBI200UB-120, 2MBI300UD-120

Conditions: $V_{DC}=600V$

$+V_{GE}=8, 10, 13, 15, 18V$

$-V_{GE}=15V$

$T_j=125^{\circ}C$

R_G (Recommended value) = 2.2Ω (2MBI150UA-120)

3.0Ω (2MBI200UB-120)

1.1Ω (2MBI300UD-120)

Results: V_{GE} - I_{SC} characteristics Fig. 1

Definition of I_{SC} : Saturated current at short circuit condition

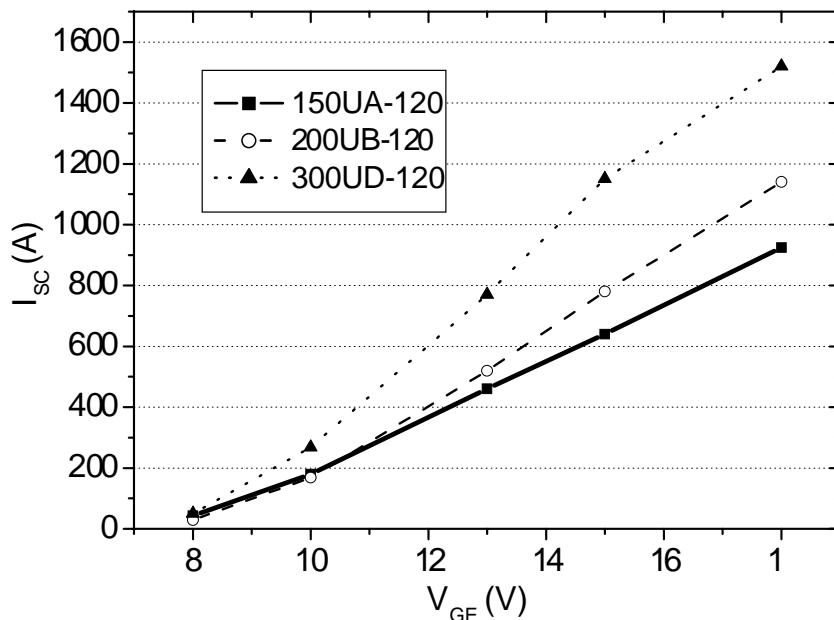
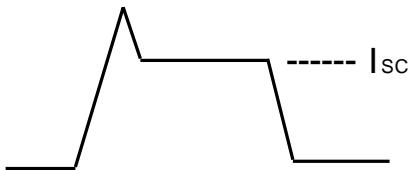


Fig. 1 V_{GE} - I_{SC} characteristics

Waveforms: 2MBI150UA-120 Fig. 2 to Fig. 6

2MBI200UB-120 Fig. 7 to Fig. 11

2MBI300UD-120 Fig. 12 to Fig. 16

2MBI150UA-120

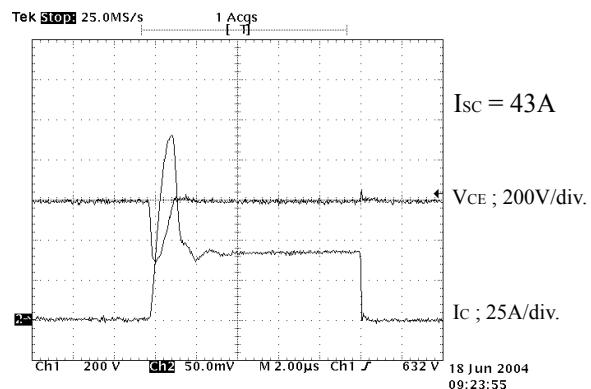


Fig. 2 $V_{GE}=8V$

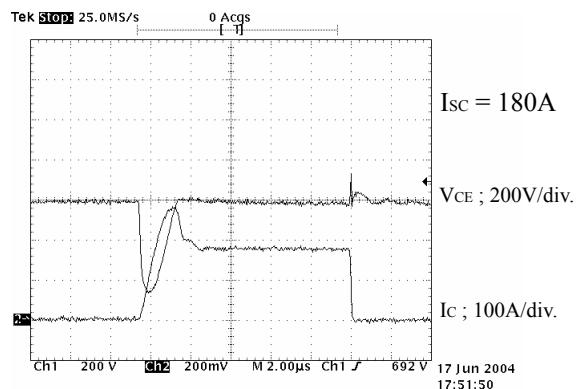


Fig. 3 $V_{GE}=10V$

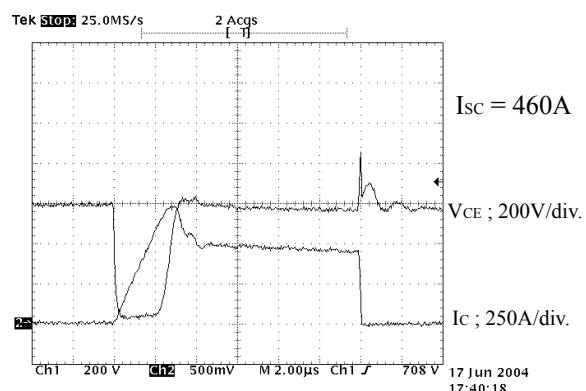


Fig. 4 $V_{GE}=13V$

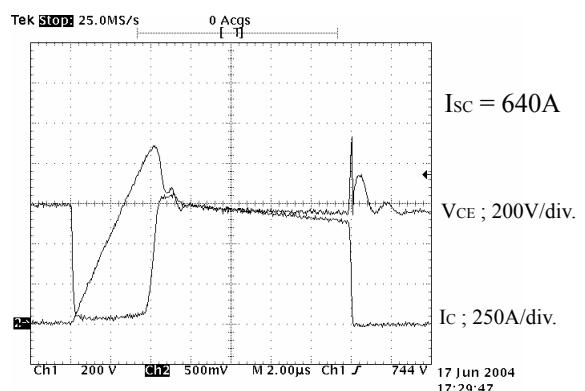


Fig. 5 $V_{GE}=15V$

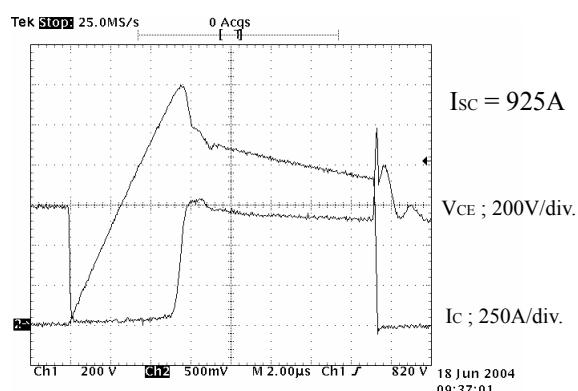


Fig. 6 $V_{GE}=18V$

2MBI200UB-120

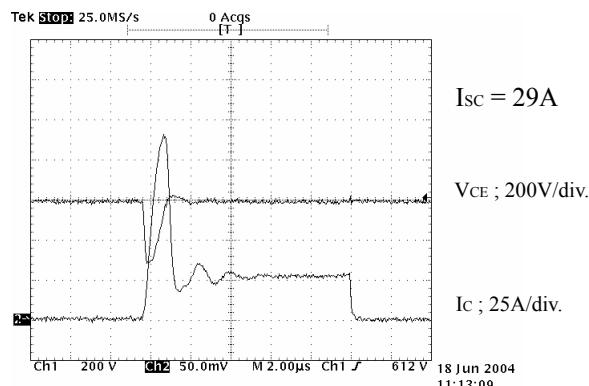


Fig. 7 $V_{GE}=8V$

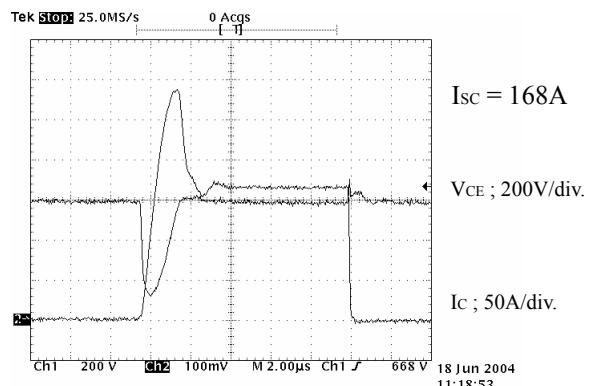


Fig. 8 $V_{GE}=10V$

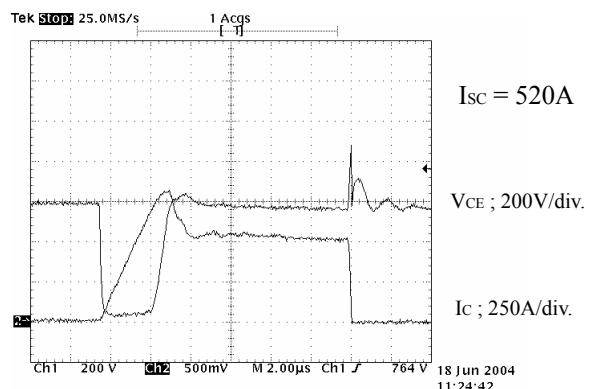


Fig. 9 $V_{GE}=13V$

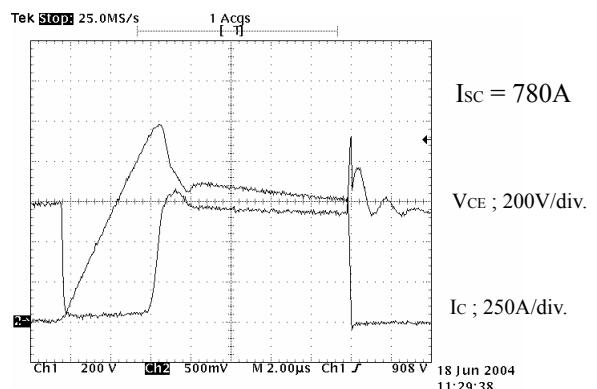


Fig. 10 $V_{GE}=15V$

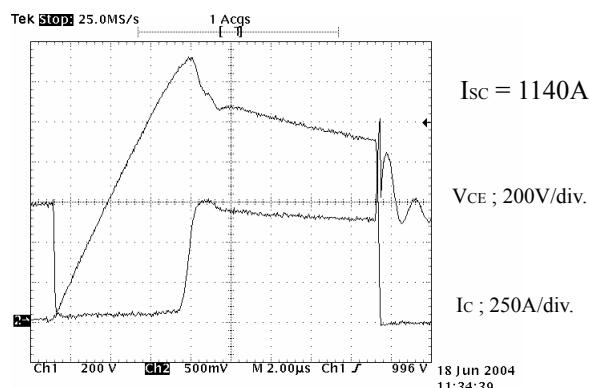


Fig. 11 $V_{GE}=18V$

2MBI300UD-120

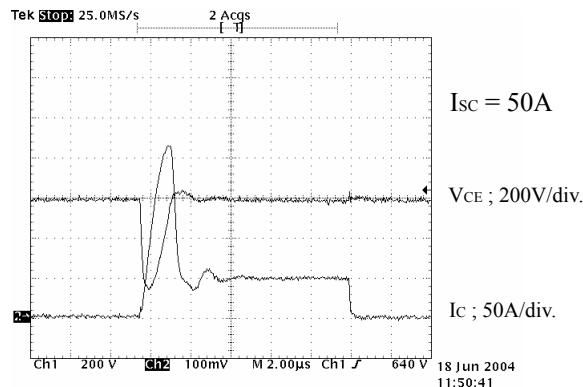


Fig. 12 $V_{GE}=8V$

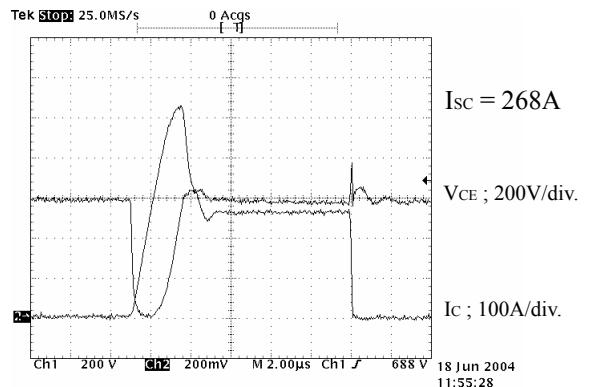


Fig. 13 $V_{GE}=10V$

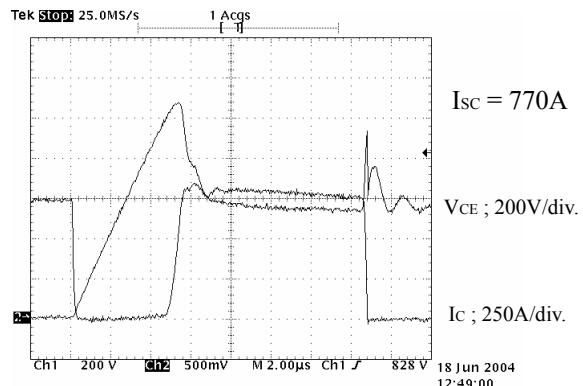


Fig. 14 $V_{GE}=13V$

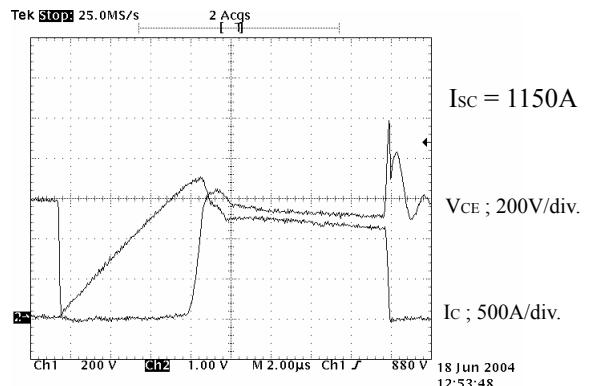


Fig. 15 $V_{GE}=15V$

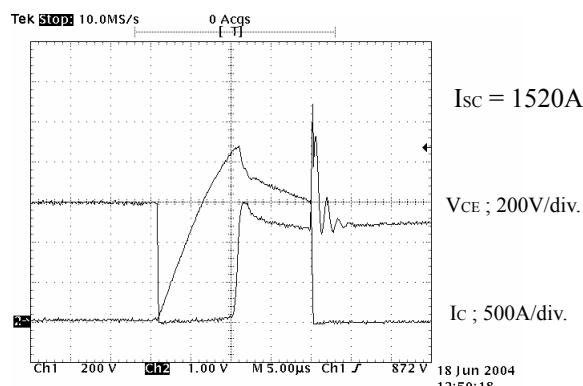
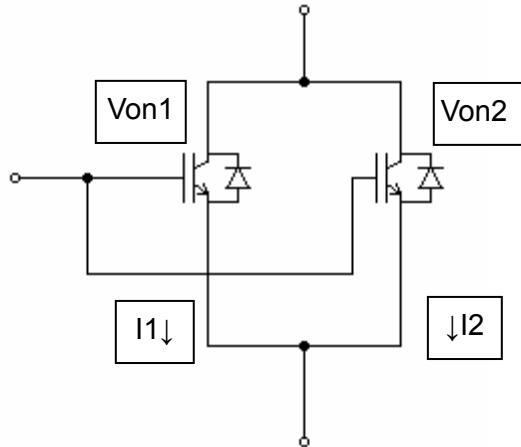


Fig. 16 $V_{GE}=18V$

FUJI IGBT Modules U Series

2 in one-package module parallel connection application 1200V

Current imbalance in parallel connection

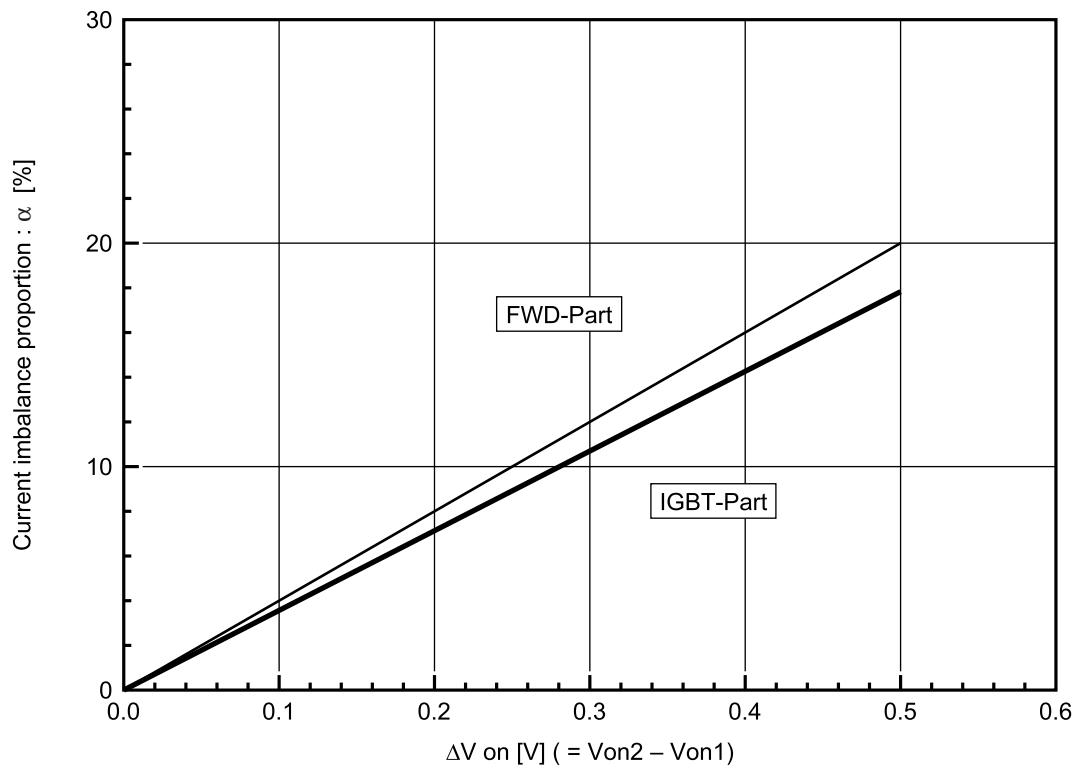


Configuration and equation

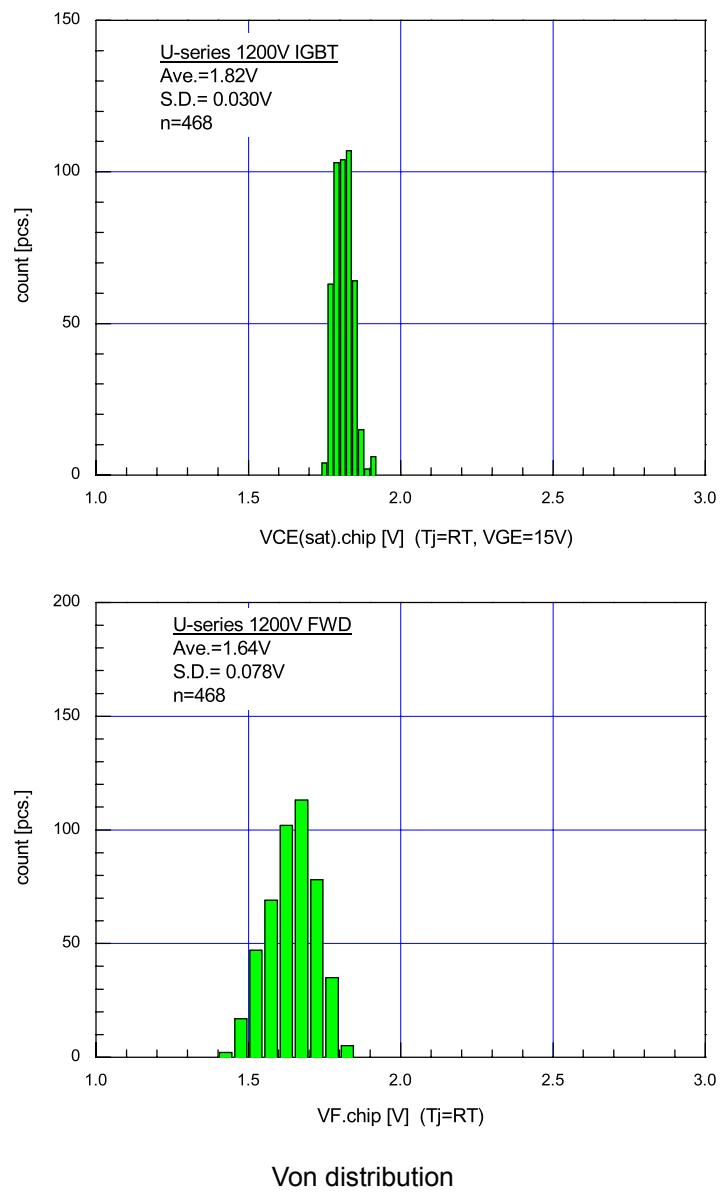
$$\Delta V_{on} = V_{on2} - V_{on1}$$

Current imbalance was caused by difference between Von1 and Von2, current will be divided to I1 and I2 respectively. In this case, the current imbalance rate is defined as following equation.

$$\alpha = [I_1 / I_c(\text{ave}) - 1] \times 100(\%)$$



$V_{CE(sat)}$, V_F distribution



Parallel connection application (Von classification)

Applicable types: 2MBI300UC-120, 2MBI300UD-120, 2MBI300UE-120, 2MBI450UE-120

Spec.	$V_{CE(sat)}$ rank	V_F rank	Current Imbalance rate (Derating rate for parallel connection)
Standard	0.5V	0.5V	20% maximum
Selection (-03)	0.3V 1-rank	0.25 – 0.3V 4-rank	13% maximum

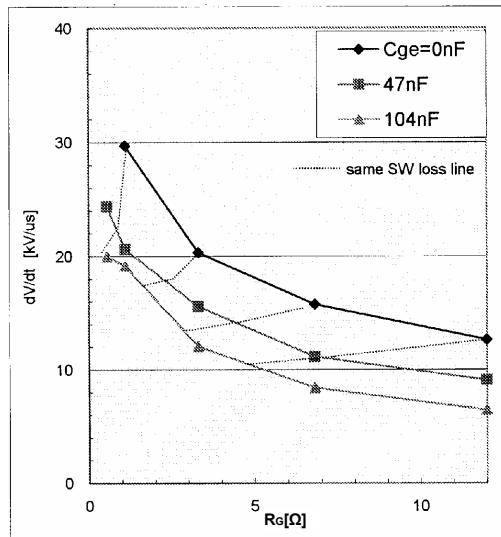
The standard part can be used to parallel connection application with 20% of current imbalance rate. If lower current imbalance rate is necessary, selection version (-03 at end of type number) is recommended. In this case, same rank device must be used to same arm of inverter leg.

FUJI IGBT Modules U Series

Switching loss, dv/dt vs C_{GE}, R_G 6MBI450U-120

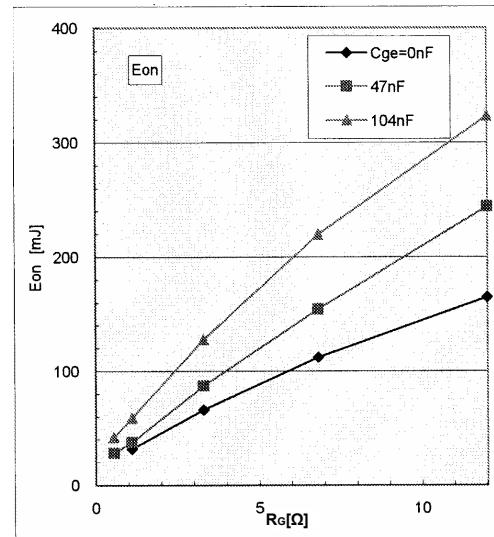
Reverse recovery dv/dt

Sample: 6MBI450U-120 #38001-11 Y-phase drive
 T_j=25°C, V_{cc}=800V, I_c=22.5A (5% of rating)
 V_{GE}=±15V, L_s=45nH, Snubber C=0



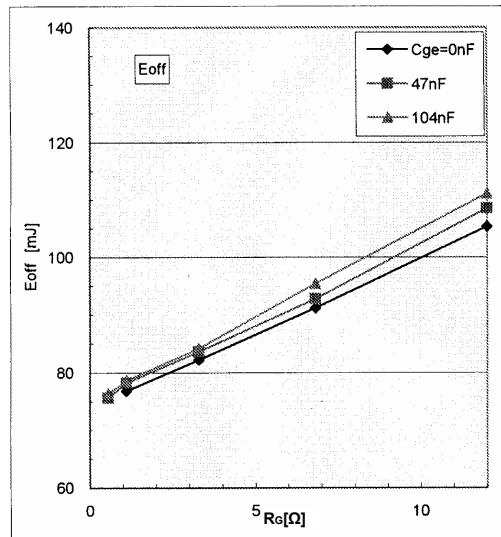
Switching loss Eon

T_j=125°C, V_{cc}=600V, I_c=450A
 V_{GE}=±15V, L_s=75nH, Snubber C=0



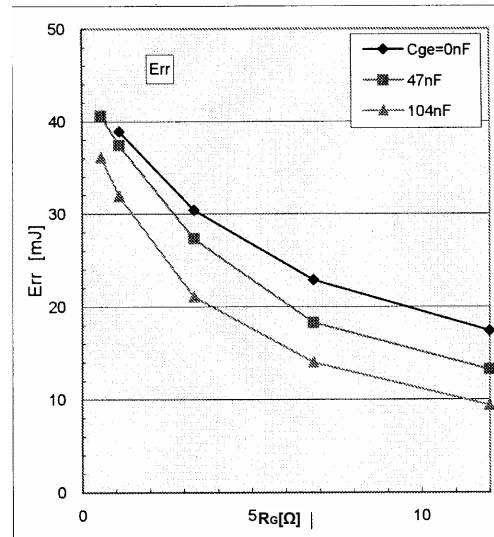
Switching loss Eoff

T_j=125°C, V_{cc}=600V, I_c=450A
 V_{GE}=±15V, L_s=75nH, Snubber C=0



Switching loss Err

T_j=125°C, V_{cc}=600V, I_c=450A
 V_{GE}=±15V, L_s=75nH, Snubber C=0

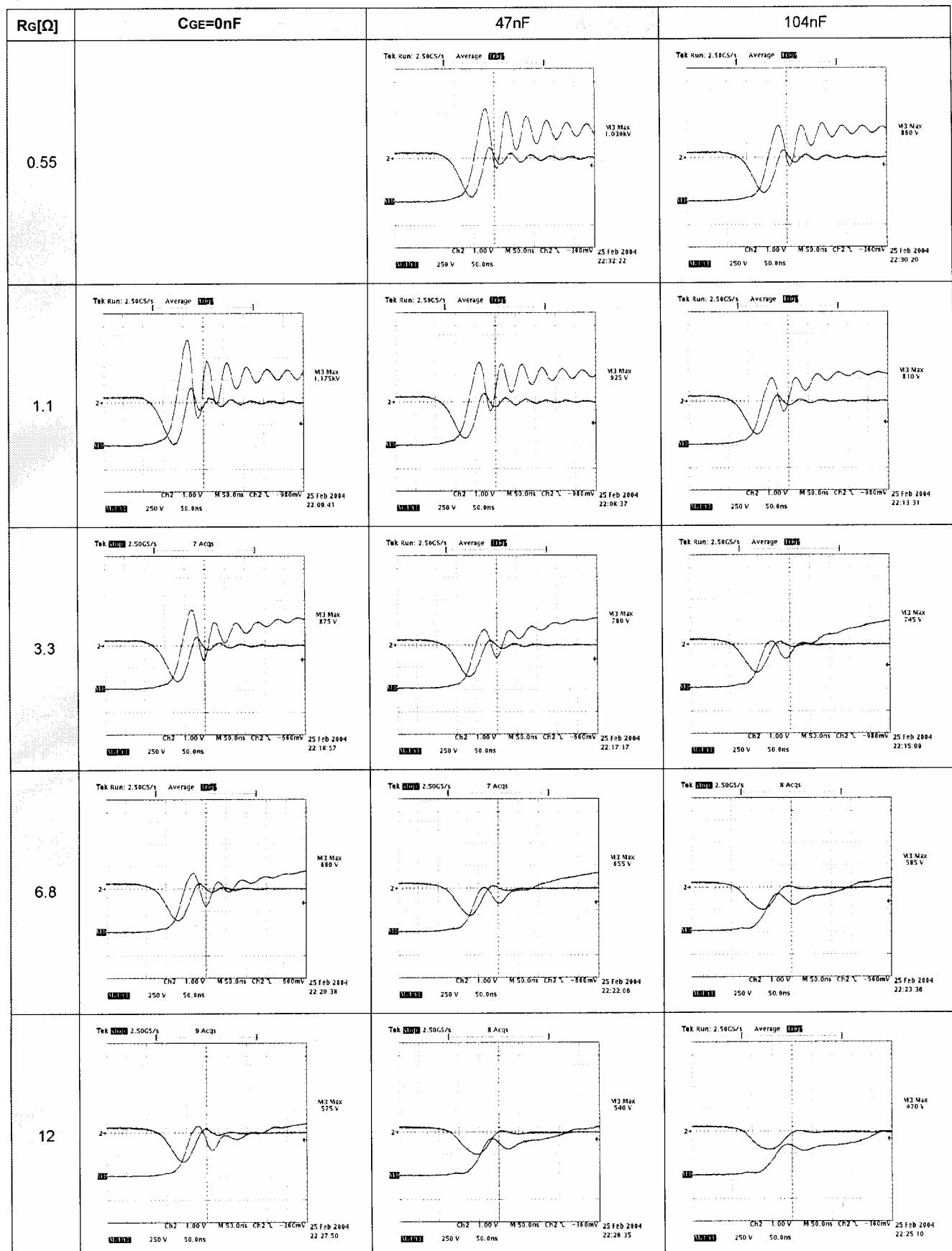


- In order to reduce dv/dt or oscillation at reverse recovery, additional C_{GE} and smaller R_G are effective.
- In order to keep same switching loss, (C_{GE} as same as Cies) + (0.7 × R_G), or (C_{GE} of 2 × Cies) + (0.5 × R_G) are recommended. These are same manner also for other 1200V U-series IGBT module.

Reverse recovery dv/dt

Sample: 6MBI450U-120 #38001-11 Y-phase drive

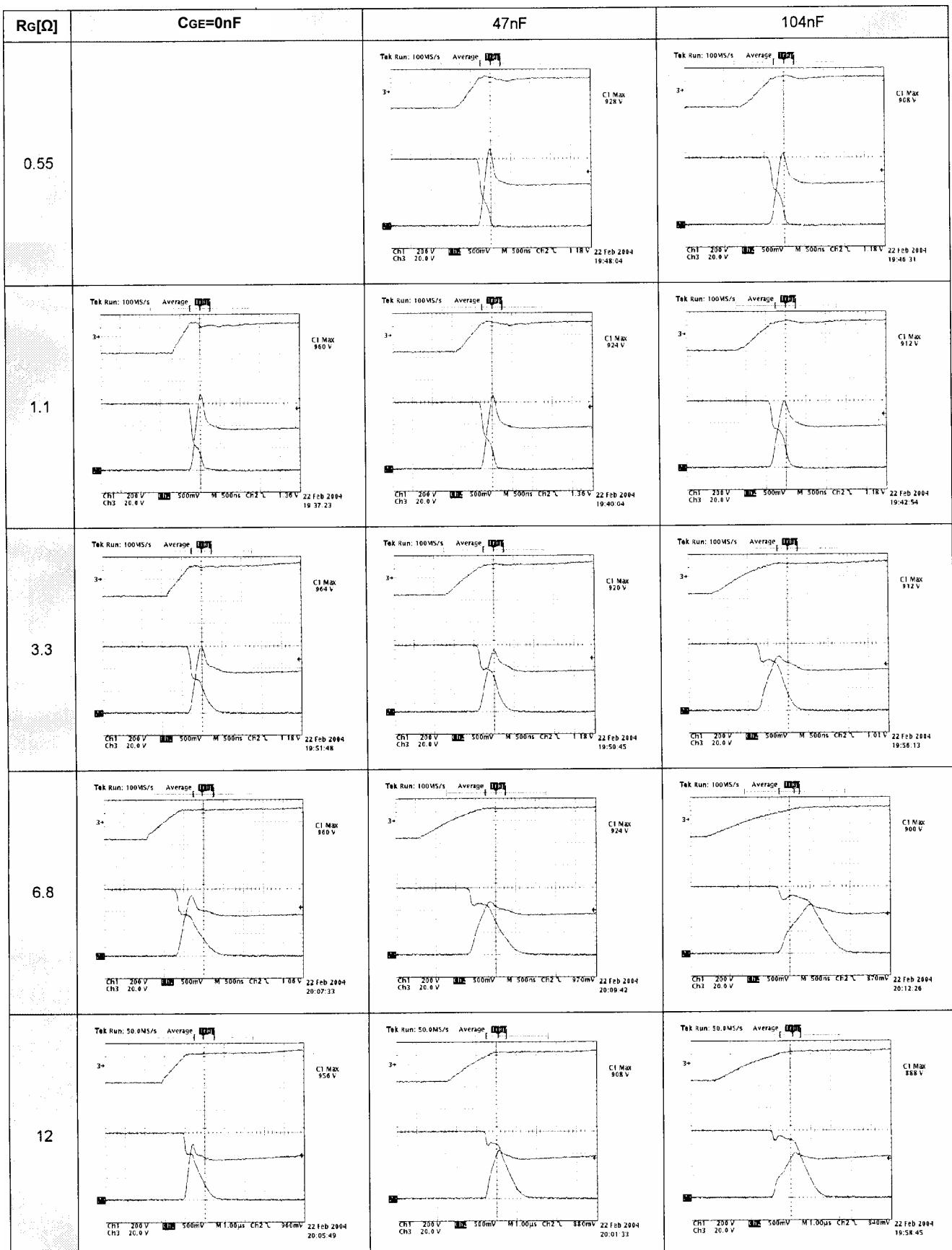
T_j=25°C, V_{cc}=800V, I_c=22.5A, V_{GE}=±15V, L_s=45nH, Snubber C=0



Eon (Latest sample)

Sample: 6MBI450U-120 #38001-11 Y-phase drive

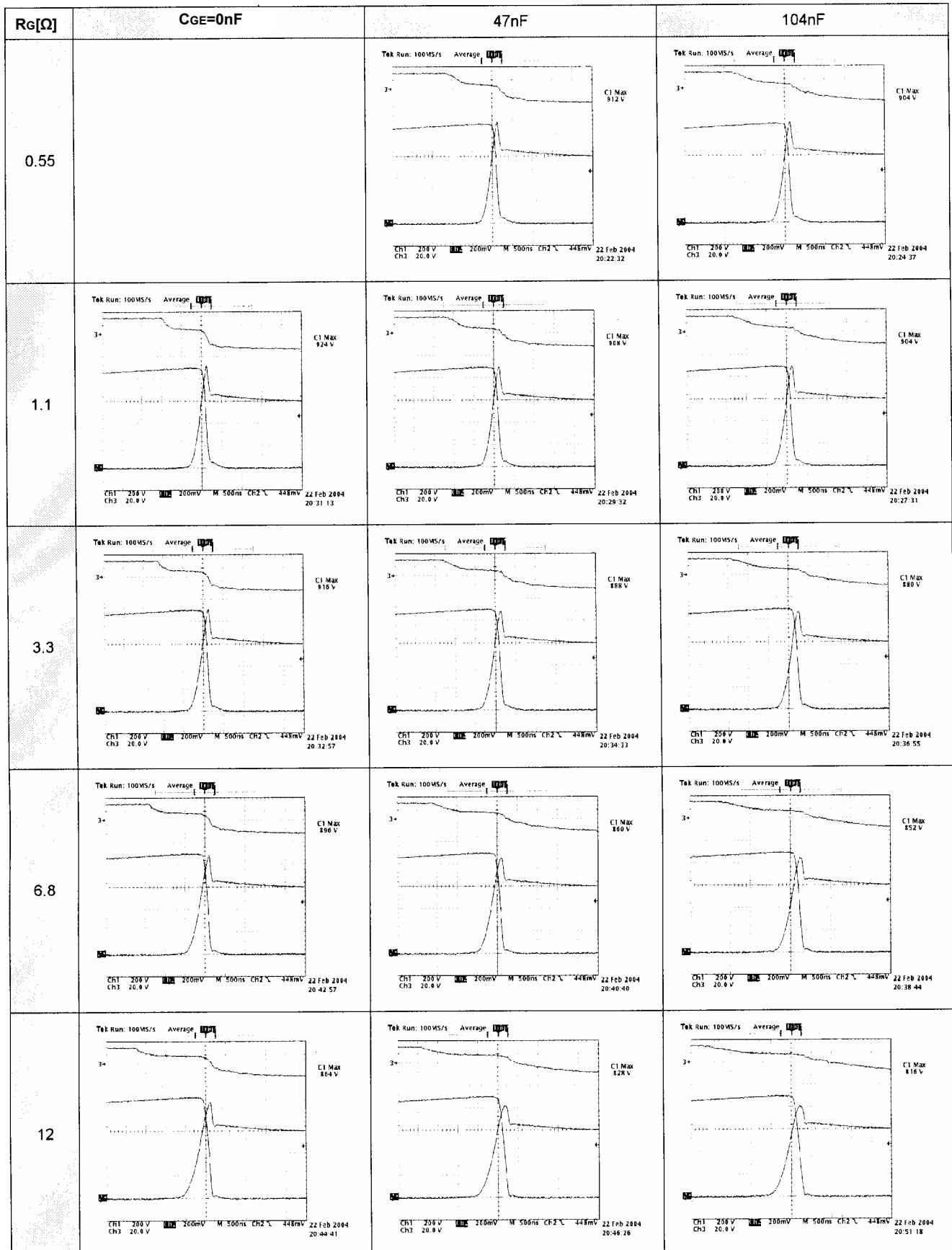
T_j=125°C, V_{cc}=600V, I_c=450A, V_{GE}=±15V, L_s=75nH, Snubber C=0



Eoff (Latest sample)

Sample: 6MBI450U-120 #38001-11 Y-phase drive

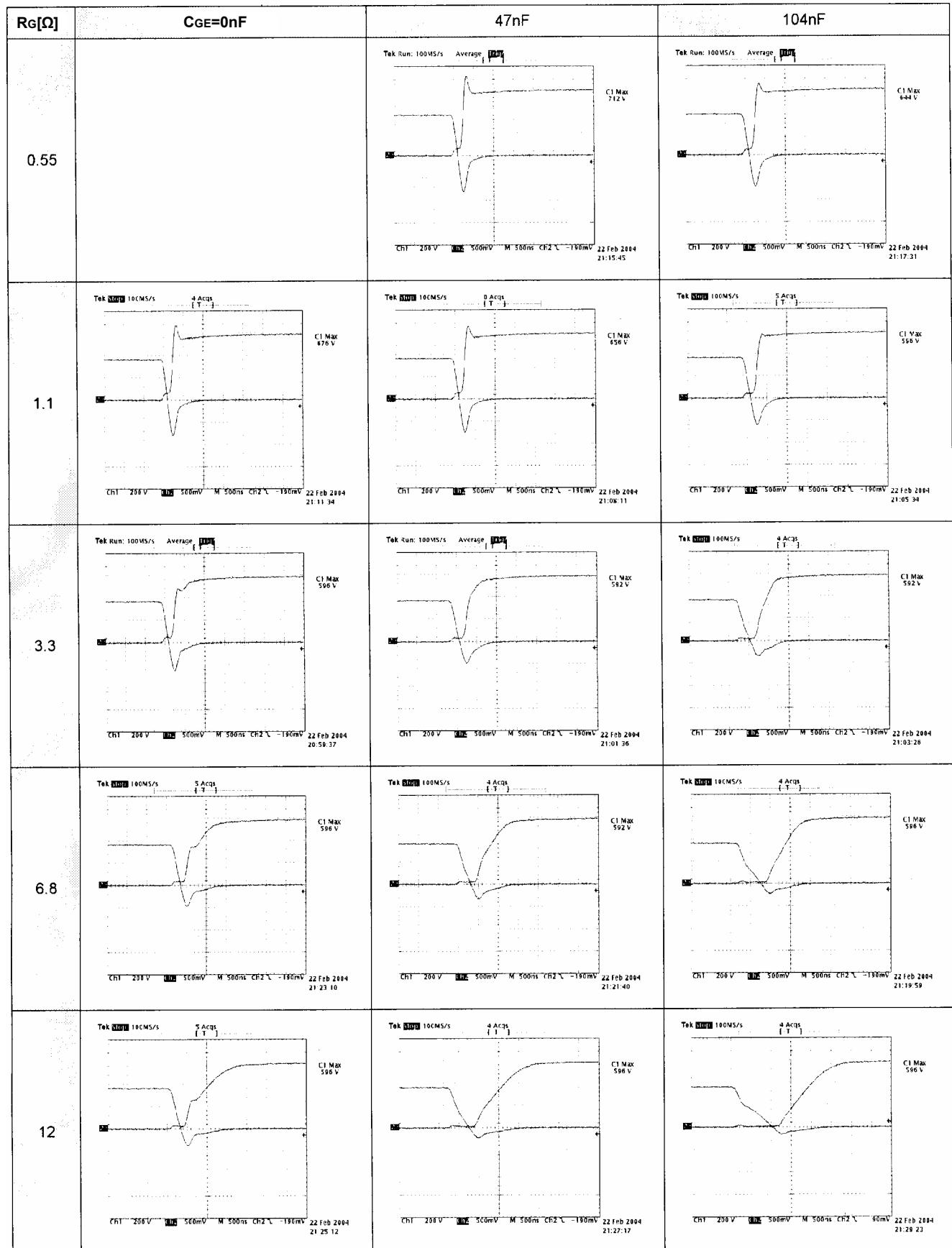
T_j=125°C, V_{cc}=600V, I_c=450A, V_{GE}=±15V, L_s=75nH, Snubber C=0



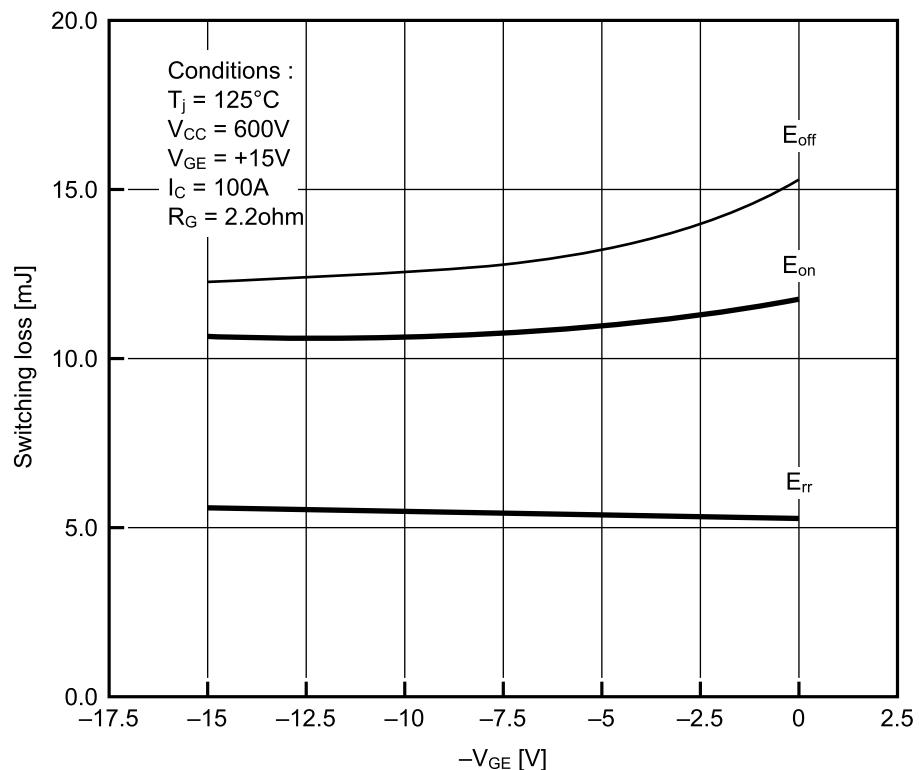
Err (Latest sample)

Sample: 6MBI450U-120 #38001-11 Y-phase drive

T_j=125°C, V_{cc}=600V, I_c=450A, V_{GE}=±15V, L_s=75nH, Snubber C=0



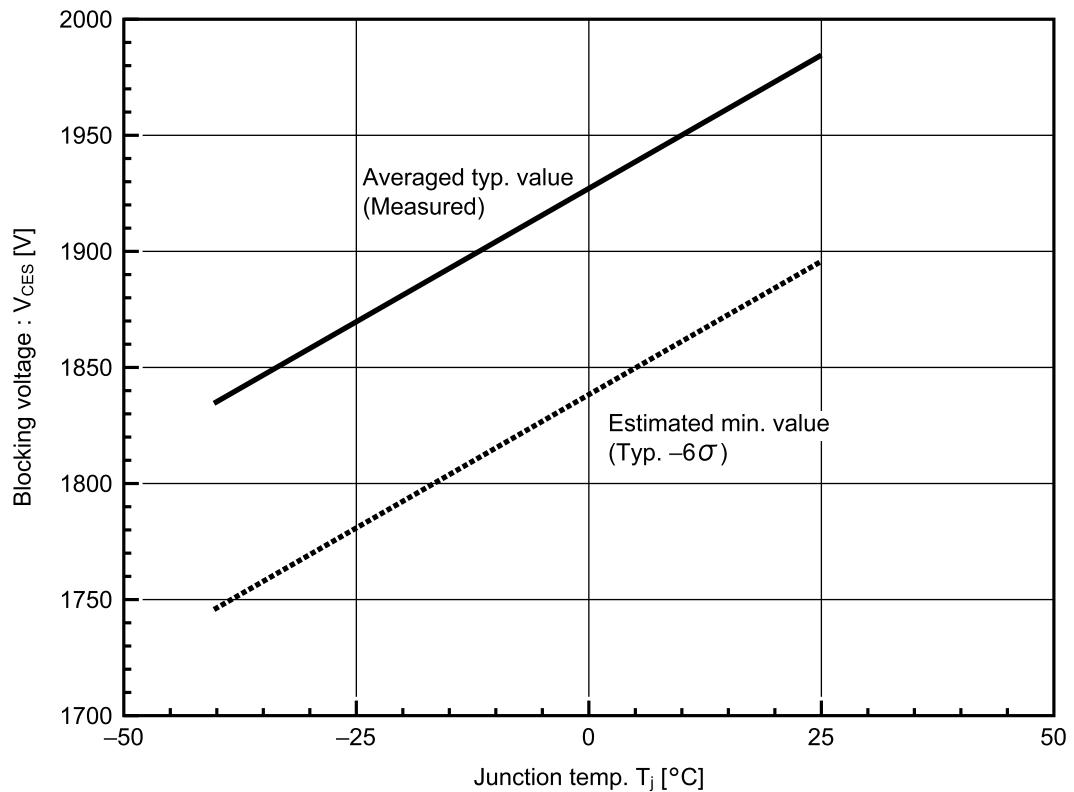
FUJI IGBT Modules U Series
-V_{GE} vs switching loss characteristics 6MBI150UB-120



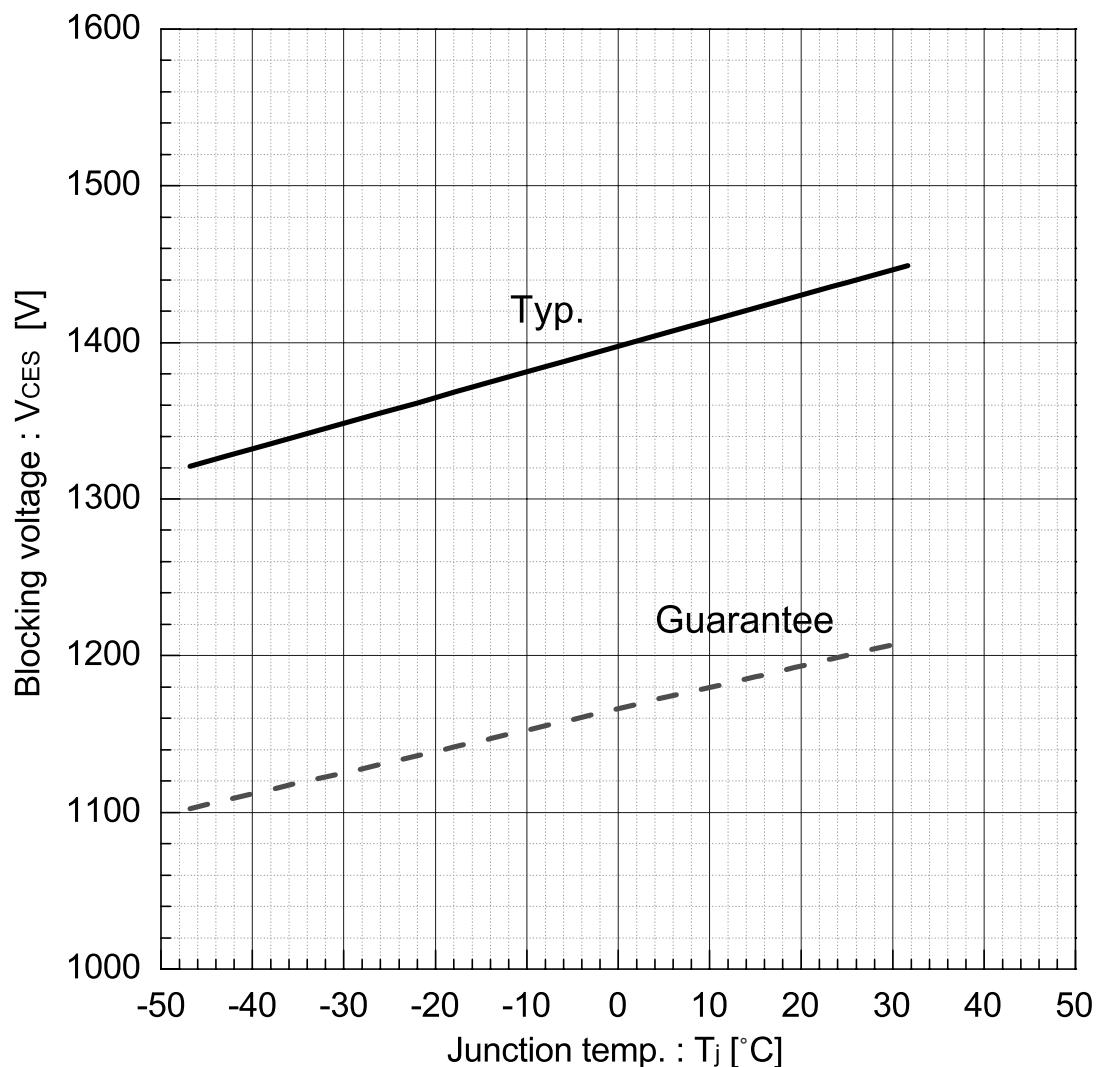
FUJI IGBT Modules U Series

Dependence of blocking voltage and junction temp. 1700V

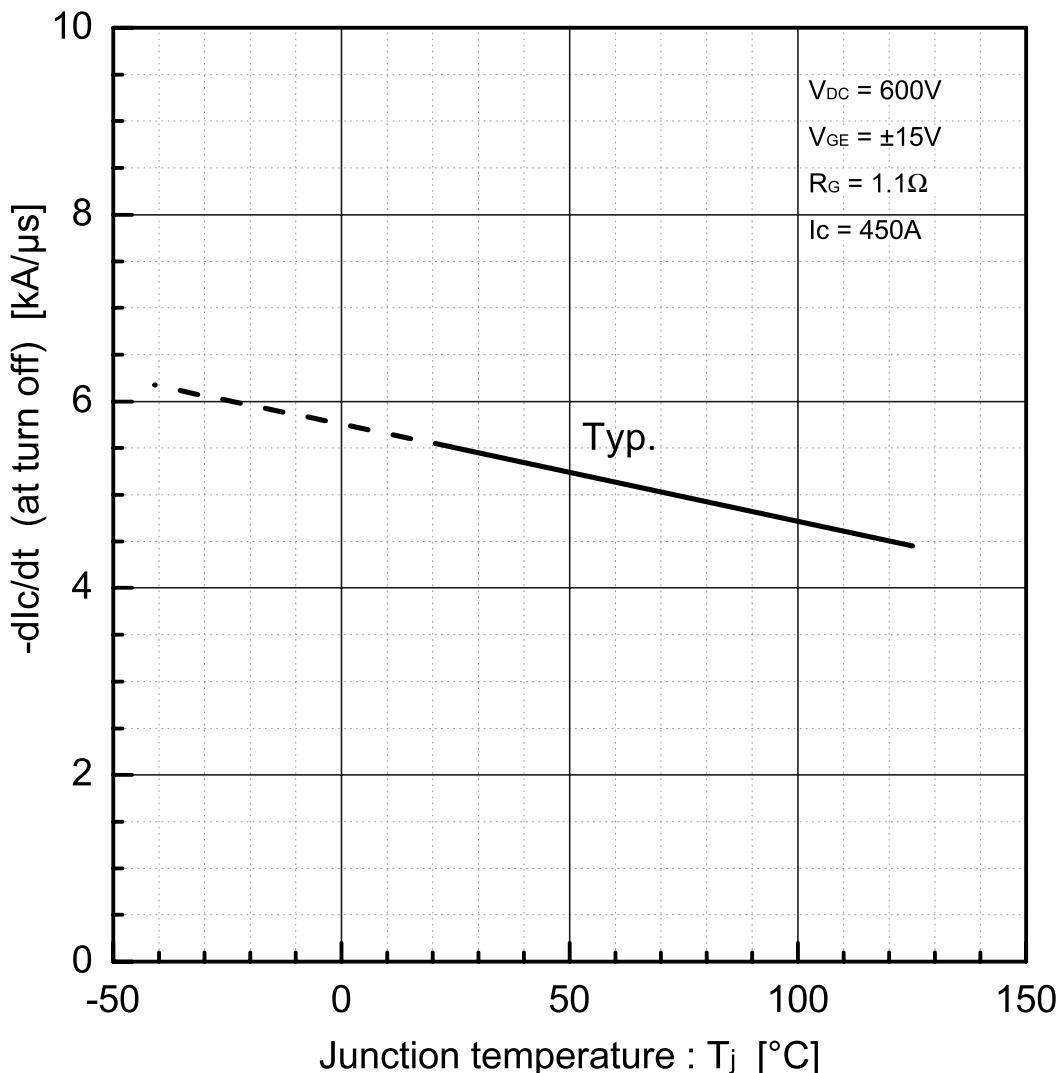
For 1700V-U series (Engineering samples), such as 6MBI450U-170 and others.



FUJI IGBT Modules U Series
V_{CES} vs T_j characteristics 1200V



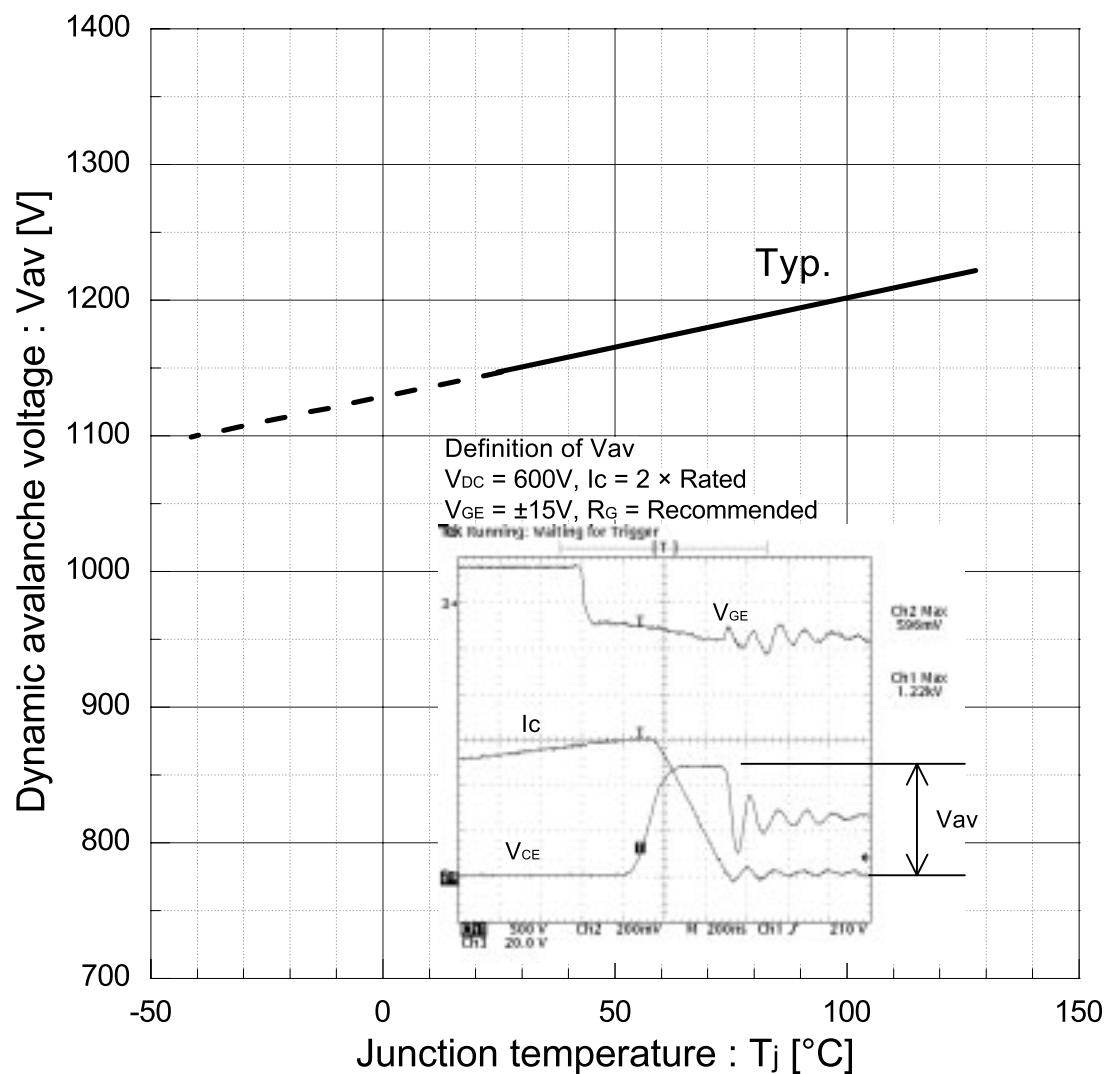
FUJI IGBT Modules U Series
-dIc/dt vs T_j characteristics 1200V, 6MBI450U-120



FUJI IGBT Modules U Series

Dynamic avalanche voltage vs T_j characteristics

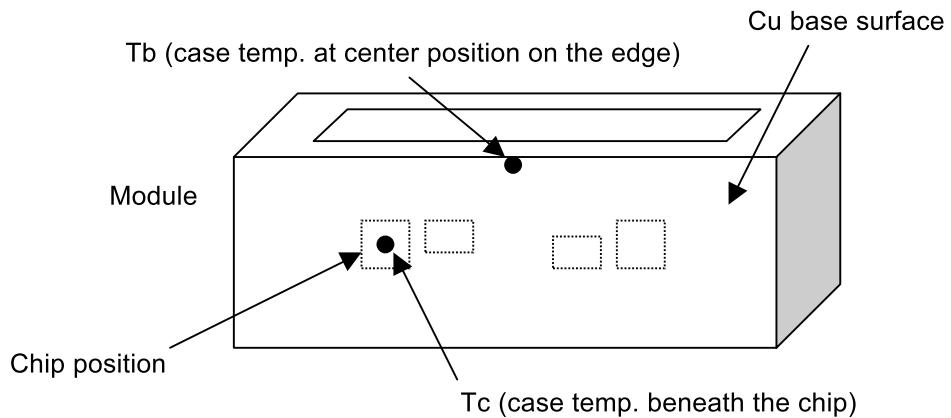
1200V 6MBI450U-120



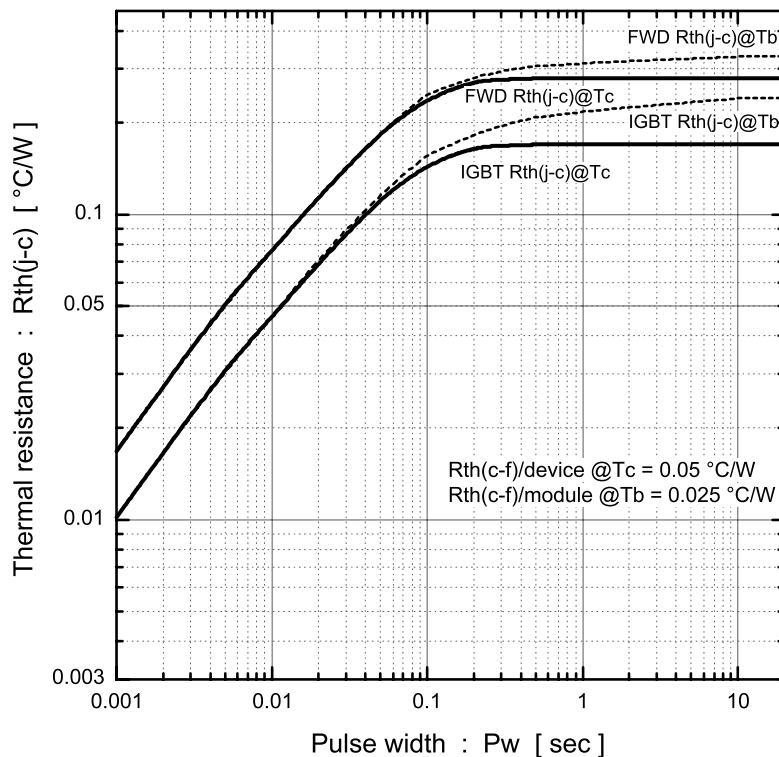
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Transient thermal impedance Calculated value

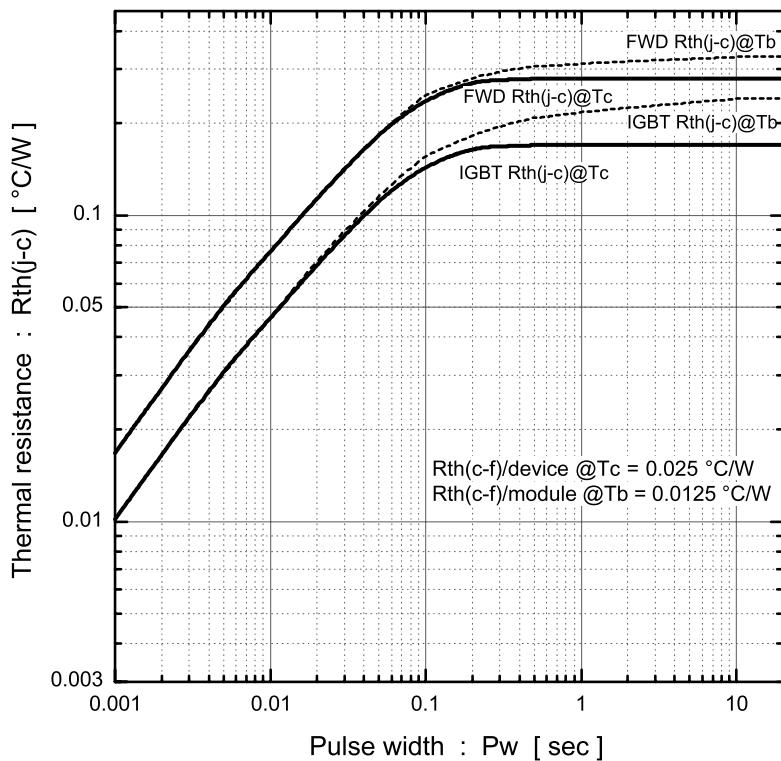
Definition of case temperature position



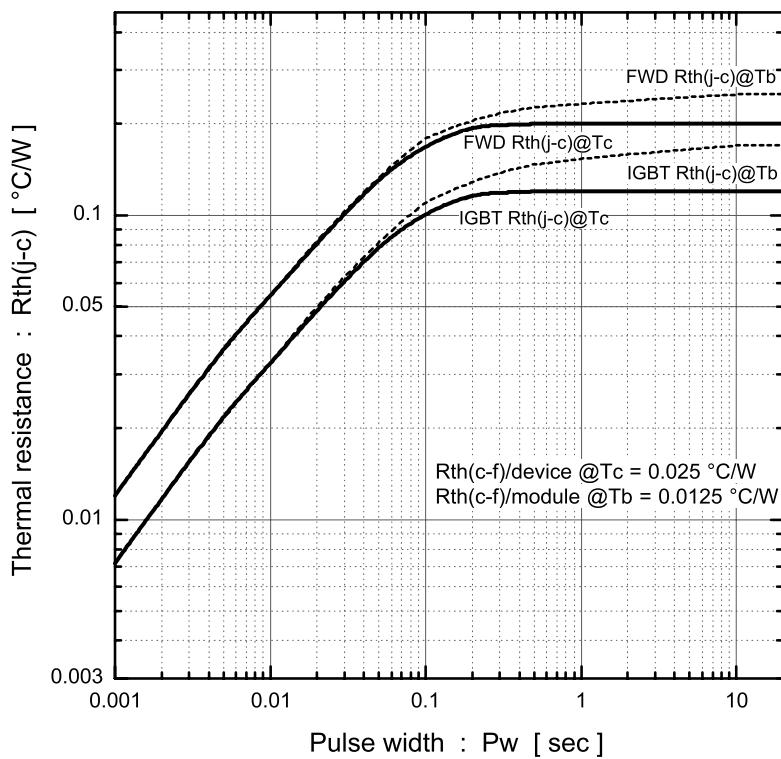
2MBI150UA-120 R_{th(j-c)}



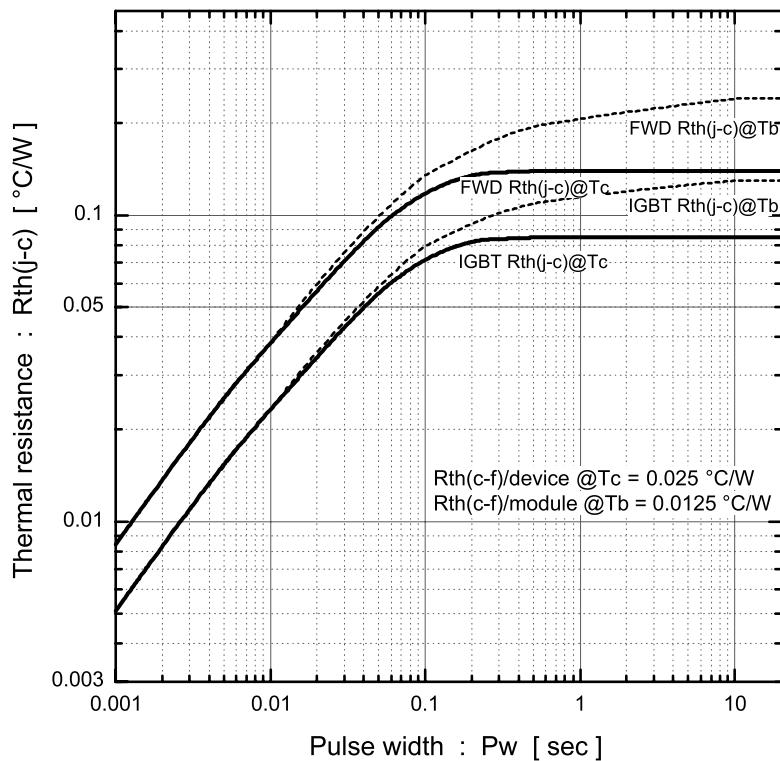
2MBI150UB-120 Rth(j-c)



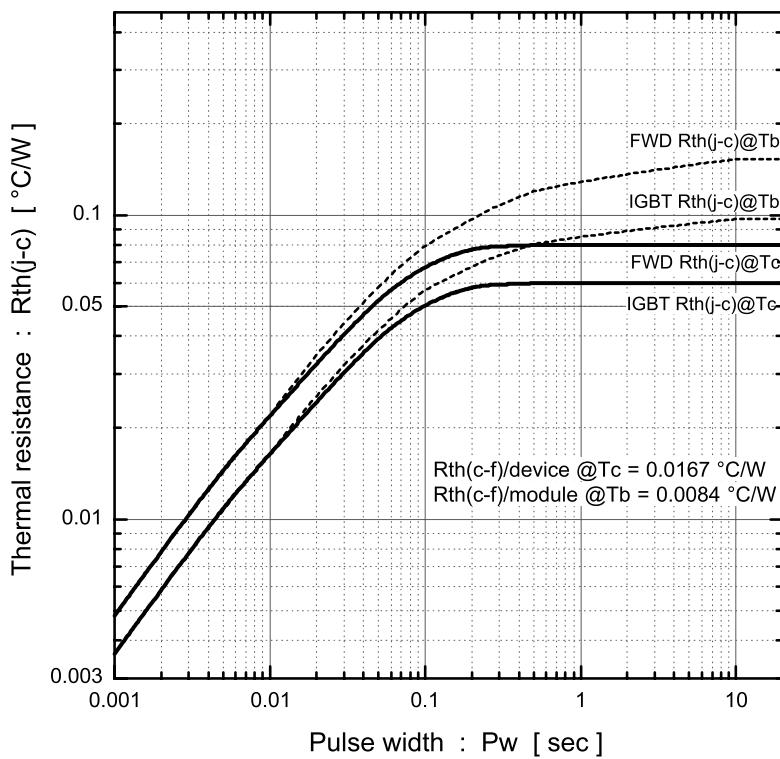
2MBI200UB-120 Rth(j-c)



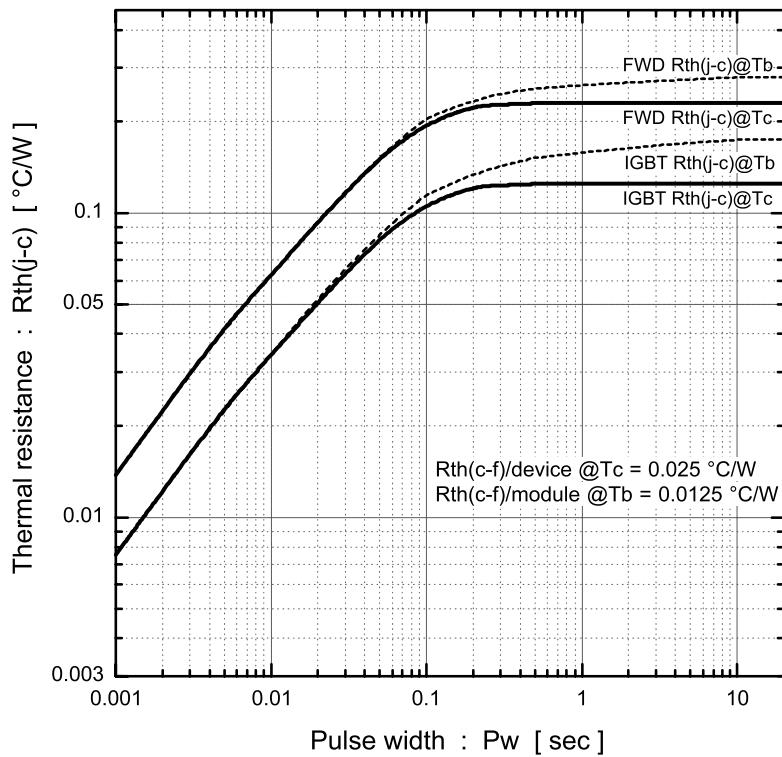
2MBI300UC-120 Rth(j-c)



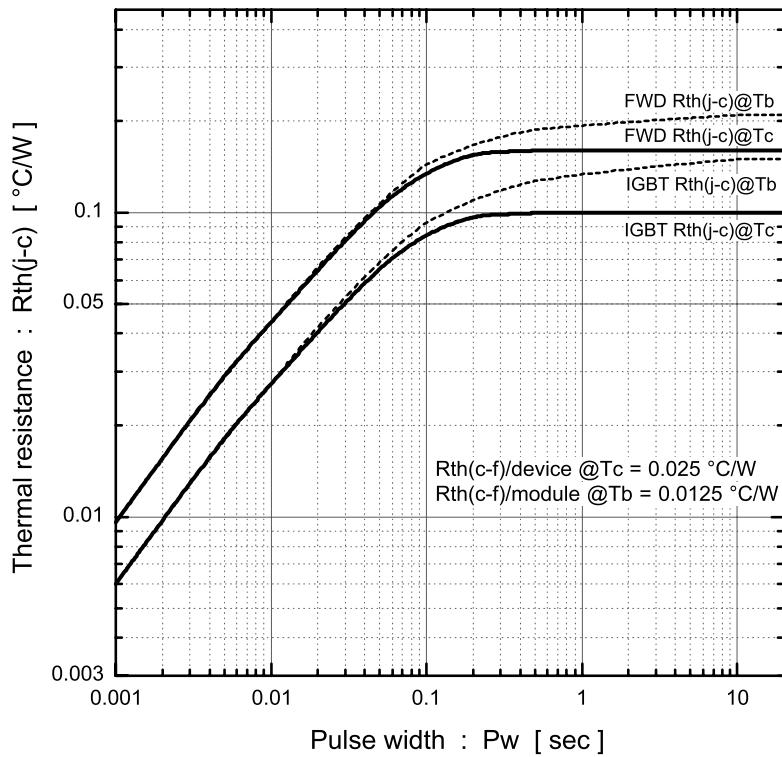
2MBI450UE-120 Rth(j-c)



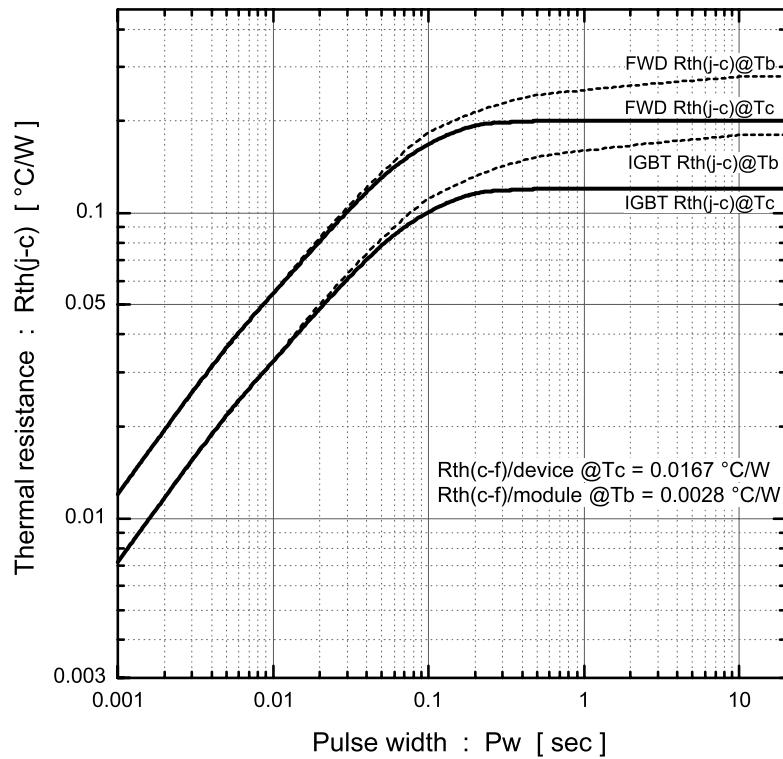
2MBI300U2B-060 Rth(j-c)



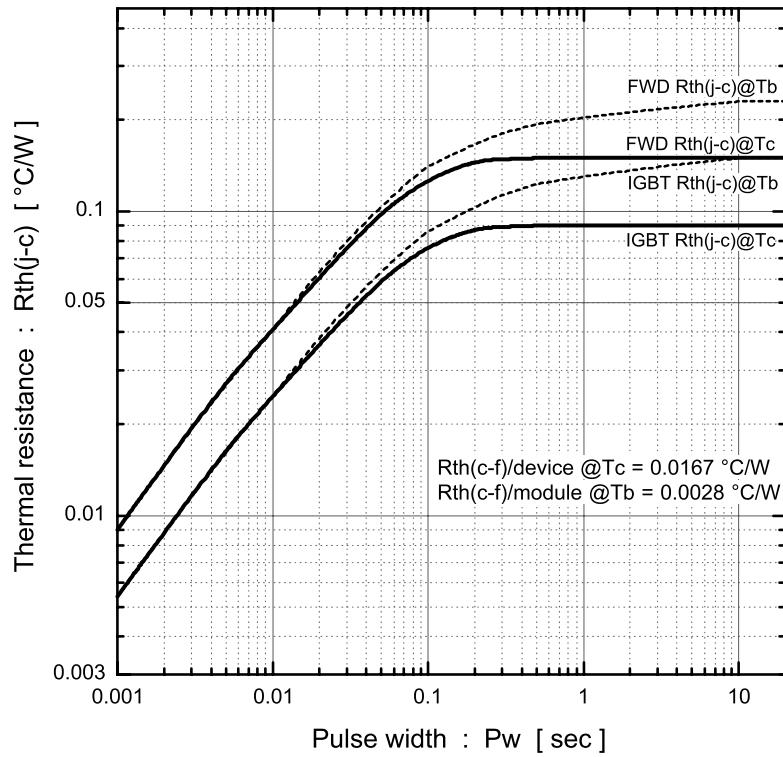
2MBI400U2B-060 Rth(j-c)



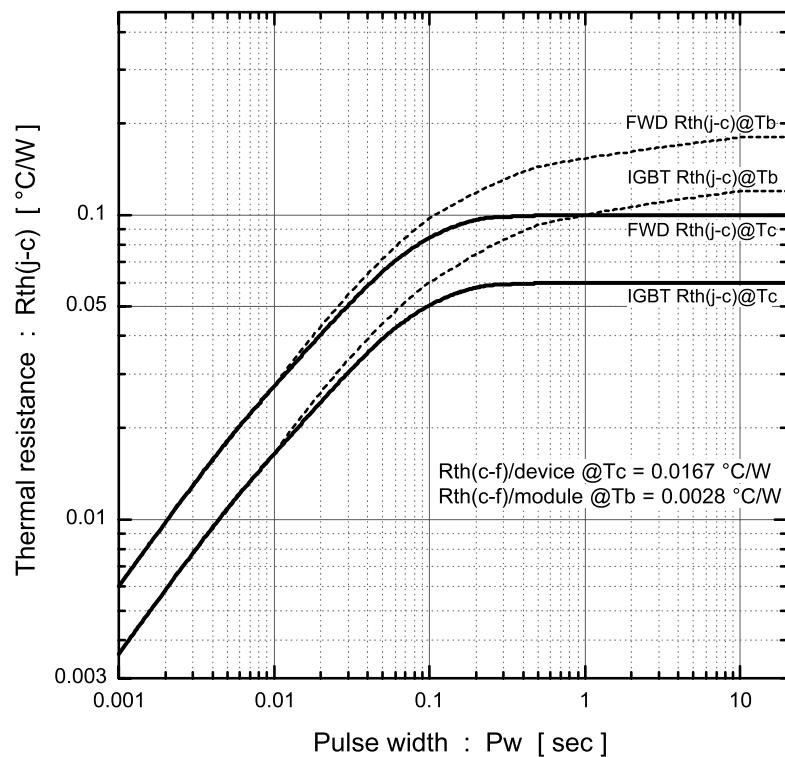
6MBI225U-120 Rth(j-c)



6MBI300U-120 Rth(j-c)



6MBI450U-120 Rth(j-c)



WARNING

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		• Personal equipment
		• Industrial robots etc.
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• Traffic-signal control equipment	• Gas leakage detectors with an auto-shut-off feature
• Emergency equipment for responding to disasters and anti-burglary devices	• Safety devices
• Medical equipment	
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• Submarine repeater equipment		
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